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reflection high energy electron diffraction (RHEED)

Any technique which measures the angular intensity distribution of electrons 'reflected' from a crystalline surface under bombardment with high energy electrons near grazing incidence. The diffraction pattern provides very surface sensitive information (information depth 1 nm) on the atomic arrangement of the top layers of a solid.

Source:
PAC, 1983, *55*, 2023 *(Nomenclature, symbols and units recommended for in situ microanalysis (Provisional))* on page 2025

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